

PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada, Ciudad. Juárez, Chihuahua, México. C.P. 32610

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2005

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

Dimensional, Electrical, Mechanical, Chemical, Mass, Force and Weighing
Devices and Thermodynamic Calibration
(As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Initial Accreditation Date:

Issue Date:

Expiration Date:

May 20, 2008

June 16, 2018

August 31, 2020

Accreditation No.:

Certificate No.:

48598

L18-277

Tracy Szerszen President/Operations Manager

Perry Johnson Laboratory Accreditation, Inc. (PJLA) 755 W. Big Beaver, Suite 1325 Troy, Michigan 48084

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: www.pjlabs.com





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Temperature Calibration,	600 °C to 800 °C	1 °C	Fluke 743B
Indication, and Control	800 °C to 1 000 °C	0.85 °C	Electrical Simulation of
Equipment used with Thermocouple Type B ^{FO}	1 000 °C to 1 550 °C	0.82 °C	Thermocouples
Thermovouple Type B	1 550 °C to 1 820 °C	0.84 °C	
Temperature Calibration,	0 °C to 150 °C	0.8 °C	
Indication, and Control Equipment used with	150 °C to 650 °C	0.75 °C	
Thermocouple Type C ^{FO}	650 °C to 1 000 °C	0.8 °C	
	1 000 °C to 1 800 °C	1.02 °C	
	1 800 °C to 2 316 °C	1.5 °C	
Temperature Calibration,	-250 °C to -100 °C	1.03 °C	
Indication and Control Equipment used with	-100 °C to -25 °C	0.63 °C	
Thermocouple Type E ^{FO}	-25 °C to 350 °C	0.41 °C	
	350 °C to 650 °C	0.65 °C	
Temperature Calibration,	-210 °C to -100 °C	-0.75 °C	
Indication and Control Equipment used with	-100 °C to -30 °C	0.7 °C	
Thermocouple Type J ^{FO}	-30 °C to 150 °C	0.6 °C	
	150 °C to 760 °C	0.75 °C	
	760 °C to 1 200 °C	0.57 °C	
Temperature Calibration,	-200 °C to -100 °C	0.82 °C	
Indication and Control Equipment used with	-100 °C to -25 °C	0.65 °C	
Thermocouple Type K ^{FO}	-25 °C to 120 °C	0.63 °C	
1 31	120 °C to 1 000 °C	0.75 °C	
	1 000 °C to 1 372 °C	0.92 °C	
Temperature Calibration,	-200 °C to -100 °C	0.9 °C	
Indication and Control Equipment used with	-100 °C to -25 °C	0.7 °C	
Thermocouple Type N ^{FO}	-25 °C to 120 °C	0.64 °C	
r Jr	120 °C to 410 °C	0.65 °C	
Temperature Calibration,	0 °C to 250 °C	1.1 °C	
Indication and Control Equipment used with	250 °C to 400 °C	0.85 °C	
Thermocouple Type R ^{FO}	400 °C to 1 000 °C	0.83 °C	
r Jr	1 000 °C to 1 767 °C	0.91 °C	



Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Temperature Calibration,	0 °C to 250 °C	0.98 °C	Electrical Simulation of
Indication and Control	250 °C to 1 000 °C	0.86 °C	Thermocouples
Equipment used with Thermocouple Type S ^{FO}	1 000 °C to 1 400 °C	0.88 °C	Fluke 743B
Thermocoupie Type 5	1 400 °C to 1 767 °C	0.97 °C	
Temperature Calibration,	-250 °C to -150 °C	1.2 °C	
Indication and Control	-150 °C to 0 °C	0.72 °C	
Equipment used with Thermocouple Type T ^{FO}	0 °C to 120 °C	0.63 °C	
Thermosoupie Type T	120 °C to 400 °C	0.61 °C	
Temperature Calibration,	-200 °C to 0 °C	1.1 °C	
Indication and Control Equipment used with	0 °C to 600 °C	0.77 °C	
Thermocouple Type U ^{FO}			
Temperature Calibration,	-200 °C to -80 °C	0.63 °C	Electrical Simulation of
Indication and Control Equipment used with	-80 °C to 0 °C	0.61 °C	RTD Output Fluke 743B
RTD Type Pt 385, $100\Omega^{FO}$	0 °C to 100 °C	0.85 °C	Fluke /43D
31	100 °C to 300 °C	0.62 °C	
	300 °C to 400 °C	0.64 °C	
	400 °C to 630 °C	0.64 °C	
Equipment to Measure	1 Kv to 28 kV	5 % of reading	Fluke 80k-40
AC Voltage Hi-Pot ^{FO}	rms @ 60Hz		
Equipment to Measure	1 kV to 20 kV	5 % of reading	
DC Voltage ^{FO}	35 kV to 40 kV		
Hi-Pot	20 Kv to 35 kV		
Equipment to Measure	110 mV	0.04 % of reading	Fluke 743B
DC Voltage ^{FO}	1.1 V	0.03 % of reading	
	11 V	0.03 % of reading	
	110 V	0.055 % of reading	
	300 V	0.055 % of reading	
Equipment to Measure AC Voltage			
At the listed frequencies ^{FO} 20 Hz to 40 Hz	1.1 V	2 % of reading	
40 Hz to 500 Hz	11. V	0.5 % of reading	
500 Hz to 1 kHz	110 V	2 % of reading	
1 kHz to 5 kHz	300 V	10 % of reading	





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure	30 mA	0.025 % of reading	Fluke 743B
DC Current ^{FO}	110 mA	0.025 % of reading	
Equipment to Measure	11 Ω	0.05 % of reading $+50 \text{ m}\Omega$	
Resistance ^{FO}	110 Ω	0.05 % of reading + $50 \text{ m}\Omega$	
	1.1 kΩ	0.05 % of reading $+500 \text{ m}\Omega$	
	11 kΩ	0.1 % of reading + 10 Ω	
Equipment to Measure	1 Hz to 109.99 Hz	0.05 Hz	
Frequency ^{FO}	110 Hz to 1 099.9 Hz	0.5 Hz	
	1.1 Hz to 10.999 kHz	5 Hz	
	11 kHz to 50 kHz	50 Hz	
Equipment to Output	0.01 mV to 329.999 9 mV	0.006 % of Output + 3 μV	Fluke 5500A
DC Voltage ^{FO}	0.01 V to 3.299 999 V	0.005 % of Output + 5 μV	
	0.01 V to 32.999 99 V	0.005 % of Output + 50 μV	
	30 V to 329.999 9 V	0.005 5 % of Output + 500 μV	
	100 V to 1 020 V	0.005 5 % of Output + 1 500 μV	
Equipment to Measure DC Power (33 mV to 1 020 V) At the listed Ampere ^{FO}		75	
3.3 mA to 8.999 mA	0.000 11 W to 9 W	0.04 % of Output	
9 mA to 32.999 mA	0.00 3 W to 33 W	0.03 % of Output	
33 mA to 89.99 mA	0.011 W to 90 W	0.04 % of Output	
90 mA to 329.99 mA	0.03 W to 330 W	0.03 % of Output	
0.33 A to 0.899 99A	0.11 W to 900 W	0.08 % of Output	
0.9 A to 2.199 99 A	0.3 W to 3 000 W	0.06 % of Output	
4.5 A to 11 A	0.99 W to 11 000 W	0.09 % of Output	
2.2 A to 4.499 9 A	0.33 W to 6 000 W	0.12 % of Output	
Equipment to Measure	0.01 mA to 3.299 99 mA	0.013 % of Output + 0.05 μA	
DC Current ^{FO}	0.01 mA to 32.999 9 mA	0.01 % of Output + 0.25 μA	
	0.01 mA to 329.999 mA	0.01 % of Output + 3.3 μA	
Equipment to Measure	1 Ω to 10.99 Ω	0.012 % of Output + 0.008 Ω	
Ohms/ Resistance LCR Meter ^{FO}	11 Ω to 32.999 Ω	0.012 % of Output + 0.015 Ω	
LCK Weter.	33 Ω to 109.999 Ω	$0.009~\%~of~Output + 0.015~\Omega$	





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure	110 Ω to 329.999 Ω	0.009 % of Output + 0.015 Ω	Fluke 5500A
Ohms/ Resistance LCR Meter ^{FO}	330 Ω to 1.099 99 kΩ	0.009 % of Output + 0.06Ω	
LCR Meter	1.1 Ω to 3.299 99 kΩ	$0.009~\%$ of Output $+~0.06~\Omega$	
	3.3 kΩ to 10.999 9 kΩ	0.009 % of Output + 0.6Ω	
	11 kΩ to 32.999 9 kΩ	0.009 % of Output + 0.6Ω	
	33 kΩ to 109.999 kΩ	0.011 % of Output + 6 Ω	
	110 kΩ to 329.999 kΩ	0.012 % of Output + 6 Ω	
	330 kΩ to 1.0999 9 MΩ	0.015 % of Output + 55Ω	
	1.1 MΩ to 3.299 99 MΩ	0.015 % of Output + 55Ω	
	$3.3~\mathrm{M}\Omega$ to $10.999~9~\mathrm{M}\Omega$	0.06 % of Output + 550 Ω	
Equipment to Measure AC Voltage – Sinewave At the listed frequencies ^{FO}			
10 Hz to 45 Hz	1 mV to 32.999 mV	0.35 % of Output + 20 μV	
45 Hz to 10 kHz	1 mV to 32.999 mV	0.15 % of Output + 20 μV	
10 kHz to 20 kHz	1 mV to 32.999 mV	0.2 % of Output + 20 μV	
20 kHz to 50 kHz	1 mV to 32.999 mV	0.25 % of Output + 20 μV	
50 kHz to 100 kHz	1 mV to 32.999 mV	0.35 % of Output + 33 μV	
100 kHz to 500 KHz	1 mV to 32.999 mV	1 % of Output + 60 μV	
Equipment to Measure AC Voltage – Sinewave At the listed frequencies ^{FO}			
10 Hz to 45 Hz	33 mV to 329.999 mV	0.25 % of Output + 50 μV	
45 Hz to 10 kHz	33 mV to 329.999 mV	0.05 % of Output + 20 μV	
10 kHz to 20 kHz	33 mV to 329.999 mV	0.1 % of Output + 20 μV	
20 kHz to 50 kHz	33 mV to 329.999 mV	0.16 % of Output + 40 μV	
50 kHz to 100 kHz	33 mV to 329.999 mV	0.24 % of Output + 170 μV	
100 kHz to 500 KHz	33 mV to 329.999 mV	0.7 % of Output + 330 μV	
Equipment to Measure AC Voltage – Sinewave At the listed frequencies ^{FO}			
10 Hz to 45 Hz	0.33 V to 3.299 99 V	0.15 % of Output + 250 μV	
45 Hz to 10 kHz	0.33 V to 3.299 99 V	0.03 % of Output + 60 μV	
10 to 20 kHz	0.33 V to 3.299 99 V	0.08 % of Output + 60 μV	
20 to 50 kHz	0.33 V to 3.299 99 V	0.14 % of Output + 300 μV	





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure AC Voltage – Sinewave At the listed frequencies ^{FO}			Fluke 5500A
50 to 100 kHz	0.33 V to 3.299 99 V	0.24 % of Output + 1 700 μV	
100 to 500 KHz	0.33 V to 3.299 99 V	0.5 % of Output + 3 300 μV	
Equipment to Measure AC Voltage – Sinewave At the listed frequencies ^{FO}			
10 Hz to 45 Hz	3.3 V to 32.999 9 V	0.15 % of Output + 2 500 μV	
45 Hz to 10 kHz	3.3 V to 32.999 9 V	0.04 % of Output + 600 μV	
10 kHz to 20 kHz	3.3 V to 32.999 9 V	0.08 % of Output + 2 600 μV	
20 kHz to 50 kHz	3.3 V to 32.999 9 V	0.19 % of Output + 5 000 μV	
50 kHz to 100 kHz	3.3 V to 32.999 9 V	0.24 % of Output + 17 000 μV	
100 kHz to 500 Hz	3.3 V to 32.999 9 V	0.15 % of Output + 2 500 μV	
Equipment to Measure AC Voltage – Sinewave At the listed frequency ^{FO}			
10 Hz to 45 Hz	33 V to 329.999 V	0.05 % of Output + 6.6 mV	
45 Hz to 10 kHz	33 V to 329.999 V	0.08 % of Output + 15 mV	
10 kHz to 20 kHz	33 V to 329.999 V	0.09 % of Output + 33 mV	
Equipment to Measure AC Voltage – Sinewave At the listed frequencies ^{FO}			
45 Hz to 1 kHz	33 V to 1 020 V	0.05 % of Output + 80 mV	
1 kHz to 5 kHz	33 V to 1 020 V	0.2 % of Output + 100 mV	
5 kHz to 10 kHz	33 V to 1 020 V	0.2 % of Output + 500 mV	
Equipment to Measure AC Current – Sinewave At the listed frequencies ^{FO}			
10 Hz to 20 Hz	0.029 mA to 0.329 99 mA	0.25 % of Output + 0.15 μA	
20 Hz to 45 Hz	0.029 mA to 0.329 99 mA	0.125 % of Output + 0.15 μA	
45 Hz to 1 kHz	0.029 mA to 0.329 99 mA	0.125 % of Output + 0.25 μA	
1 kHz to 5 kHz	0.029 mA to 0.329 99 mA	0.4 % of Output + 0.15 μA	
5 kHz to 10 kHz	0.029 mA to 0.329 99 mA	1.25 % of Output + 0.15 μA	



Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure AC Current – Sinewave At the listed frequencies ^{FO}			Fluke 5500A
10 Hz to 20 Hz	0.33 mA to 3.299 9 mA	0.2% of Output + $0.3 \mu A$	
20 Hz to 45 Hz	0.33 mA to 3.299 9 mA	0.1 % of Output + 0.3 μA	
45 Hz to 1 kHz	0.33 mA to 3.299 9 mA	0.1 % of Output + 0.3 μA	
1 kHz to 5 kHz	0.33 mA to 3.299 9 mA	0.2 % of Output + 0.3 μA	
5 kHz to 10 kHz	0.33 mA to 3.299 9 mA	0.6 % of Output + 0.3 μA	
Equipment to Measure AC Current – Sinewave At the listed frequencies ^{FO}			
10 Hz to 20 Hz	3.3 mA to 33 mA	0.6 % of Output + 3 μA	
20 Hz to 45 Hz	3.3 mA to 33 mA	0.9 % of Output + 3 μA	
45 Hz to 1 kHz	3.3 mA to 33 mA	0.6% of Output + 3μ A	
1 kHz to 5 kHz	3.3 mA to 33 mA	0.4 % of Output + 3 μA	
5 kHz to 10 kHz	3.3 mA to 33 mA	0.9 % of Output + 3 μA	
10 kHz to 20 kHz	3.3 mA to 33 mA	0.9 % of Output + 3 μA	2
Equipment to Measure AC Current – Sinewave At the listed frequencies ^{FO}			
10 Hz to 20 Hz	33 mA to 329.99 mA	0.6 % of Output + 30 μA	
20 Hz to 45 Hz	33 mA to 329.99 mA	0.9 % of Output + 30 μA	
45 Hz to 1 kHz	33 mA to 329.99 mA	0.6 % of Output + 30 μA	
1 kHz to 5 kHz	33 mA to 329.99 mA	0.4 % of Output + 30 μA	
5 kHz to 10 kHz	33 mA to 329.99 mA	0.9 % of Output + 30 μA	
10 kHz to 20 kHz	33 mA to 329.99 mA	0.9 % of Output + 30 μA	
Equipment to Measure AC Current – Sinewave At the listed frequencies ^{FO}			
10 Hz to 45 Hz	0.33 A to 2.199 99 A	0.2 % of Output + 300 μA	
45 Hz to 1 kHz	0.33 A to 2.199 99 A	0.1 % of Output + 300 μA	
1 kHz to 5 kHz	0.33 A to 2.199 99 A	0.75 % of Output + 300 μA	
Equipment to Measure AC Current – Sinewave At the listed frequencies ^{FO}			
45 Hz to 65 Hz	2.2 A to 11 A	0.06 % of Output + 2 000 μA	





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

Electrical

MEASURED QUANTITY,	RANGE	CALIBRATION	CALIBRATION
INSTRUMENT OR GAUGE	(AND SPECIFICATION	AND MEASUREMENT	EQUIPMENT AND
	WHERE APPROPRIATE)	CAPABILITY EXPRESSED	REFERENCE
		AS AN UNCERTAINTY (±)	STANDARDS USED
Equipment to Measure			Fluke 5500A
AC Current – Sinewave			
At the listed frequencies ^{FO}			
65 Hz to 500 Hz	2.2 A to 11 A	0.1 % of Output + 2 000 μA	
500 Hz to 1 kHz	2.2 A to 11 A	0.33 % of Output + 2 000 μA	
Equipment to Measure	0.33 μF to 0.499 9 μF	0.5 % of Output + 0.01 μF	
Capacitance LCR Meter ^{FO}	0.5 μF to 1.099 9 μF	0.5 % of Output + 0.01 μF	
LCK Meter	1.1 μF to 3.299 9 μF	0.5 % of Output + 0.01 μF	
	3.3 μF to 10.999 μF	0.5 % of Output + 0.01 μF	
	11 μF to 32.999 μF	0.25 % of Output + 0.1 μF	
	33 μF to 109.99 μF	0.25 % of Output + 0.1 μF	
	110 μF to 329.99 μF	0.25 % of Output + 0.3 μF	
	0.33 μF to 1.099 9 μF	0.25 % of Output + 1 μF	
	1.1 μF to 3.299 9 μF	0.35 % of Output + 3 μF	
	3.3 μF to 10.999 μF	0.35 % of Output + 10 μF	
	11 μF to 32.999 μF	0.4 % of Output + 30 μF	
	33 μF to 109.99 μF	0.5 % of Output + 100 μF	
	110 μF to 329.99 μF	0.7 % of Output + 300 μF	
	330 μF to 1.1 mF	1 % of Output + 300 μF	
Equipment to Measure	45 Hz to 1 kHz	0.05 % of Output	Fluke PM6680B
AC Frequency Generators ^{FO}	1 kHz to 10 kHz	0.2 % of Output	
	10 kHz to 20 kHz	0.25 % of Output	
	20 kHz to 50 kHz	0.25 % of Output	
Equipment to Measure AC Oscilloscopes ^{FO}	10 kHz to 50 kHz	0.2 % of Output	Fluke 5500A

Mechanical

MEASURED QUANTITY,	RANGE	CALIBRATION	CALIBRATION
INSTRUMENT OR GAUGE	(AND SPECIFICATION	AND MEASUREMENT	EQUIPMENT AND
	WHERE APPROPRIATE)	CAPABILITY EXPRESSED	REFERENCE
		AS AN UNCERTAINTY (±)	STANDARDS USED
Pressure Gages ^{FO}	68.95 Pa to 68 947.57 kPa	0.5 % of reading	Fluke 743B
			(ANSI/ASME B40.100)
			Druck DPI0610 PV411





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

Mechanical

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Torque Analyzer ^F	0.044 N·m to 11.298 N·m	2 % of reading	Wheel Mass Class F
Torque Transducer ^F	0.044 N·m to 11.298 N·m	2 % of reading	
Torque Wrenches ^F	0.044 N·m to 11.298 N·m	2 % of reading	
	0.44 N·m to 500 N·m (0.098 lbf to 112 lbf)	0.2 % of reading	Digital Torque Wrench Tester ANJ-500
Direct Verification of			ASTM D2240
Durometer Hardness			
Tester Types			
A, B, C, D, O			
Durometer Indentor Spring Types A, B, E & O ^F	0.55 N to 8.05 N	0.7 N	Load Cell
Indirect Verification of	20 HRB to 59 HRB	1.05 HRB	Standardized Test Blocks
Rockwell Hardness	60 HRB to 84 HRB	0.72 HRB	ASTM E 18
Testers HRB ^O	85 HRB to 100HRB	0.55 HRB	
Indirect Verification of	20 HRC to 34 HRC	0.5 HRC	
Rockwell Hardness	35 HRC to 59 HRC	0.4 HRC	
Testers HRC ^O	60 HRC to 70 HRC	0.35 HRC	
Indirect Verification of	42 HR30N to 54 HR30N	0.55 HR30N	7
Rockwell Hardness	55 HR30N to 76 HR30N	0.4 HR30N	
Testers HR30N ^o	77 HR30N to 82 HR30N	0.35 HR30N	

Mass, Force, and Weighing Devices

wass, rorce, and werg	ining Devices		
MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Balances Class I & II ^O	1 mg to 500 mg (Res.= 0.1 mg)	0.16 mg	Class 1
Scales Class III ^O	0.1 kg to 1 kg (Res.= 0.002 gr)	0.026 g	Class 6
Scales and Platforms Class III ^O	1 kg to 150 kg (Res.= 0.02 kg)	0.12 kg	Class F
	151 kg to 1 500 kg (Res.= 0.2 kg)	$(2.25 \times 10^{-1} + 4.3 \times 10^{-5} \text{Wt}) \text{ kg}$	
Verification of Testing Machines in Tension and	1 N to 889 N (1 lbf to 200 lbf	0.1 % of reading	Class F Weights
Compression ^O	88.9 N to 4.41 kN (20 lbf to 1 000 lbf)	0.5 N (0.11 lbf)	Calibration Load Cell
	889.6 N to 44.13 kN (200 lbf to 10 000 lbf)	3.8 N (0.85 lbf)	





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

Dimensional

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Vernier Dial and Digital	0.05 in to 20 in	(547 + 9L) μin	Set Block Gage
Calipers ^F	(1.27 mm to 508 mm)	$[(14 + 0.009L) \mu m]$	_
Micrometers ^F	0.05 in to 20 in	(286 + 17.1L) μin	
	(1.27 mm to 508 mm)	$[(7.3 + 0.017 1L) \mu m]$	
Vernier Dial and Digital	0.05 in to 20 in	(547 + 9L) μin	
Height Gages ^F Metal Rules ^F	(0 mm to 508 mm)	$[(14 + 0.009L) \mu m]$	
Metal Rules ^F	0.039 in to 20 in	0.013 in	Rule Master Stage
	maximum		Micrometer/Comparator & Reticle
Surface Plates ^O	10 in to 72 in Diagonal	$(57.87 + 2.57L) \mu in$	Autocollimator Repeat Reading Fixture
Dial Indicators ^F	0.05 in to 20 in	130 µin	Set Block Gage
	(1.27 mm to 508 mm)	(3.3 µm)	S
Plain Limit Gages ^F	0.01 in to 2 in	25 µin	Laser Micrometer Zygo
	(0.25 mm to 50.80 mm)	(0.64 μm)	,
Thread Plug Gages ^F	M 0.6-0.9 mm to	0.05 mm	Screw Micrometer
(Straight Thread Pitch)	M 1 - 1.75 mm		Pitch Master Combo
Thread Ring Gages	M 0.6- 0.9 mm to	0.05 mm	
(Straight Thread Pitch)	M 1 - 1.75 mm		
Measuring Projectors ^O	0.01 in to 10 in	2 200 µin	Glass Scale
	(0.025 mm to 25.4 mm)	(56 µm)	
Measuring Microscopes ^O	0.01 in to 4 in	580 µin	
	(0.25 mm to 101.6 mm)	(15 μm)	
Gages Block	0.05 in to 4 in	$(5.92 + 1.78 L) \mu in$	Starrett 715 Amplifier
Grade 0, 1, 2 ^F			JIS B 7506
Precision Level ^F	180°	1°	Master Level JIS B 7510
Optical Comparators ^O X Axis Linearity Y Axis Linearity	0.05 in to 12 in	(143 + 17.5L) μin	Stage Micrometer/ Comparator & Reticle/ Gage Block Set
Optical Comparators	10X	0.03 %	
Magnification ^O	20X	0.03 %	
	31.25X	0.03 %	
Optical Comparators Squarness ^O	90°	0.1°	
Optical Comparators Angularity ^O	0° to 360°	0.1°	Angle Plate Set/ Reticle
Video Measurement System ^o X Axis Linearity Y Axis Linearity	0.05 in to12 in maximum	(143 + 17.5L) μin	Stage Micrometer/ Comparator & Reticle/ Gage Block Set





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

Dimensional

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Video Measurement System Angularity ^O	0° to 360°	0.1°	Angle Plate Set/ Reticle
Video Measurement	10X	0.03 %	Stage Micrometer/
System Magnification ^O	20X	0.03 %	Comparator & Reticle/Gage Block Set
Magnification	31.25X	0.03 %	Relicie/Gage block Set
Video Measurement System Squareness ^O	90°	0.1°	
Protactors ^O	1° to 180°	0.3°	Angle Plate Set/ Reticle
Trumeter- Odometers ^O	1 m to 100 m	0.5 % of reading	Direct Measure-Totalizer Counter

Chemical

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
pH Meters ^{FO}	4 pH to 10 pH	0.07 pH	pH Standard Solution
Conductivity Meters ^{FO}	3 μS/cm to 12 880 μS/cm	$(8.65 \times 10^{-1} + 1.16 \times 10^{-2} \text{S}) \mu\text{S/cm}$	Conductivity Solution
Humidity	33 % RH to 75 % RH	3 % RH	Aqueous Solutions
Hygrometers ^F			ASTM E104-02

Thermodynamic

MEASURED QUANTITY, INSTRUMENT OR GAUGE	RANGE (AND SPECIFICATION WHERE APPROPRIATE)	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Infrared Temperature Measuring Devices ^{FO}	20 °C to 50 °C	0.5 °C	Black Body Wahl HSICBB-P

1. The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represents the smallest measurement uncertainty attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is typically expressed at a confidence level of 95 % using a coverage factor k (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.





Laboratorios Industriales de México

Rancho Santa Clara No. 2919, Fracc. Pradera Dorada Ciudad Juárez, Chihuahua, México C.P. 32610 Contact Name: Jorge González. Phone: 656-289-3732

Accreditation is granted to the facility to perform the following calibrations:

- 2. The laboratories range of calibration capability for all disciplines for which they are accredited is the interval from the smallest calibrated standard to the largest calibrated standard used in performing the calibration. The low end of this range must be an attainable value for which the laboratory has or has access to the standard referenced. Verification of an indicated value of zero in the absence of a standard is common practice in the procedure for many calibrations but by its definition it does not constitute calibration of zero capacity.
- 3. The presence of a superscript F means that the laboratory performs calibration of the indicated parameter at its fixed location. Example: Outside Micrometer^F would mean that the laboratory performs this calibration at its fixed location.
- 4. The presence of a superscript O means that the laboratory performs calibration of the indicated parameter onsite at customer locations. Example: Outside Micrometer would mean that the laboratory performs this calibration onsite at the customer's location.
- 5. The presence of a superscript FO means that the laboratory performs calibration of the indicated parameter both at its fixed location and onsite at customer locations. Example: Outside Micrometer^{FO} would mean that the laboratory performs this calibration at its fixed location and onsite at customer locations.
- 6. Measurement uncertainties obtained for calibrations performed at customer sites can be expected to be larger than the measurement uncertainties obtained at the laboratories fixed location for similar calibrations. This is due to the effects of transportation of the standards and equipment and upon environmental conditions at the customer site which are typically not controlled as closely as at the laboratories fixed location.
- 7. The term L represents length in inches or millimeters as appropriate to the uncertainty statement.
- 8. The term Wt represents weight in pounds or grams (including SI multiple and submultiple units) appropriate to the uncertainty statement.
- 9. The term S represents conductivity in μ S/cm or S/m as appropriate to the uncertainty statement.